

<b>Notice of References Cited</b>	Application/Control No. 10/725,687		Applicant(s)/Patent Under Reexamination BEHAN, EDGAR G.	
	Examiner Truc T. T. Nguyen		Art Unit 2833	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
<input checked="" type="checkbox"/>	A	US-6,505,073	01-2003	Gramse, Leonard J.	607/37
<input checked="" type="checkbox"/>	B	US-6,205,358	03-2001	Haeg et al.	607/36
<input checked="" type="checkbox"/>	C	US-6,183,305	02-2001	Doan et al.	439/668
<input checked="" type="checkbox"/>	D	US-6,428,336	08-2002	Akerfeldt, Dan	439/263
<input checked="" type="checkbox"/>	E	US-6,162,101	12-2000	Fischer et al.	439/729
<input checked="" type="checkbox"/>	F	US-6,428,368	08-2002	Hawkins et al.	439/271
<input checked="" type="checkbox"/>	G	US-4,764,132	08-1988	Stutz, Jr., William H.	607/116
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.